Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10791209	HAHN, SOONKAP	
Examiner	Art Unit	
Skowronek, Karlheinz R	1631	

SEARCHED					
Class	Subclass	Date	Examiner		
1					

SEARCH NOTES				
Search Notes	Date	Examiner		
Search Terms: SHORT TANDEM REPEAT, STRP, VARIABLE NUMBER TANDEM REPEAT, POLYMORPHISM, CGG REPEAT, FRAGILE X SYNDROME, AVIDIN, MUTATION DETECTION, PCR, GENOMIC DNA, MICROARRAY, COLORIMETRIC, VNTR, MICROSATELITES, QUANTITATION; Inventor Search	4/6/2007	KRS		
EAST: SEARCH TERMS	4/6/2007	KRS		
STN: MEDLINE, CAPLUS, BIOSIS, EMBASE, PASCAL, SCISEARCH; SEARCH TERMS	4/6/2007	KRS		

	INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner	